## Applicant(s)/Patent Under Reexamination Application/Control No. 10/029,673 EHRMANN-PATIN ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 2621 Shervin Nakhjavan **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,785,815 B1	08-2004	Serret-Avila et al.	713/176
	В	US-6,711,710 B2	03-2004	Jiang et al.	714/784
	С	US-6,587,944 B2	07-2003	Yeung et al.	713/176
	D	US-6,320,829 B1	11-2001	Matsumoto et al.	369/47.12
	E	US-			·
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-		-	
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N		:			
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	P					
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	s	•				
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

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